TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

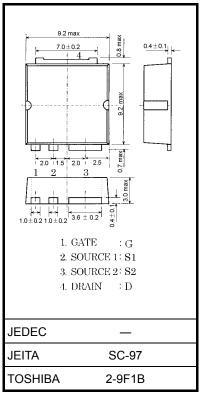
2SK3443

Switching Regulator, DC-DC Converter and Motor Drive Applications

- Low drain-source ON resistance: $RDS(ON) = 50 m\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 9 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 100 \ \mu A (V_{DS} = 150 \ V)$
- Enhancementmode: $V_{th} = 3.0$ to 5.0 V ($V_{DS} = 10$ V, $I_D = 1$ mA)

Absolute Maximum Ratings (Ta = 25°C)

| Characteristics | | Symbol | Rating | Unit | |
|--|----------------|------------------|------------|------|--|
| Drain-source voltage | | V _{DSS} | 150 | V | |
| Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$) | | V _{DGR} | 150 | V | |
| Gate-source voltage | | V _{GSS} | ±30 | V | |
| Drain current | DC (Note 1) | I _D | 30 | А | |
| | Pulse (Note 1) | I _{DP} | 120 | A | |
| Drain power dissipation (Tc = 25° C) | | PD | 125 | W | |
| Single pulse avalanche energy (Note 2) | | E _{AS} | 468 | mJ | |
| Avalanche current | | I _{AR} | 30 | А | |
| Repetitive avalanche energy (Note 3) | | E _{AR} | 12.5 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature range | | T _{stg} | –55 to 150 | °C | |



Weight: 0.74 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Thermal Characteristics

| Characteristics | Symbol | Max | Unit |
|-------------------------------------|------------------------|------|------|
| Thermal resistance, channel to case | R _{th (ch-c)} | 1.00 | °C/W |

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2 $~V_{DD}$ = 50 V, T_{ch} = 25 $^{\circ}C$ (initial), L = 773 $\mu H,~R_{G}$ = 25 $\Omega,~I_{AR}$ = 30 A

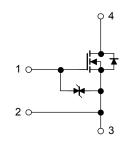
Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.

Circuit Configuration

Notice:

Please use the S1 pin for gate input signal return. Make sure that the main current flows into the S2 pin.



Unit: mm

Electrical Characteristics (Note 4) (Ta = 25°C)

| Chara | acteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|----------------|----------------------|--|-----|------|-----|------|
| Gate leakage current | | I _{GSS} | $V_{GS}=\pm 25~V,~V_{DS}=0~V$ | _ | | ±10 | μA |
| Drain cut-off curre | ent | IDSS | $V_{DS} = 150 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ | | | 100 | μA |
| Drain-source brea | akdown voltage | V (BR) DSS | $I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$ | 150 | | _ | V |
| Gate threshold vo | oltage | V _{th} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$ | 3.0 | | 5.0 | V |
| Drain-source ON | resistance | R _{DS (ON)} | $V_{GS} = 10 \text{ V}, \text{ I}_{D} = 15 \text{ A}$ | _ | 50 | 55 | mΩ |
| Forward transfer | admittance | Y _{fs} | $V_{DS} = 10 \text{ V}, \text{ I}_{D} = 15 \text{ A}$ | 4.5 | 9 | _ | S |
| Input capacitance | | C _{iss} | | _ | 2030 | _ | |
| Reverse transfer capacitance | | C _{rss} | $V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$ | _ | 340 | _ | pF |
| Output capacitance | | C _{oss} | | _ | 1200 | _ | |
| Switching time | Rise time | tr | $\begin{array}{c} 10 \text{ V} \\ \text{V}_{GS1} \\ 0 \text{ V} \\ \text{G} \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \begin{array}{c} G \circ \end{array} \\ \hline G \circ \end{array} $ \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \end{array} \\ \hline G \circ \\ \hline G \circ \end{array} \\ \hline G \circ \\ \hline G \circ \\ \hline G \circ \end{array} \\ \hline G \circ \\ \\ \hline G \circ \\ \hline G \circ \\ \\ \\ \hline G \circ \\ \\ \\ \end{array} \\ \\ \\ \end{array} \\ \\ \\ \end{array} \\ \\ \\ \end{array} \\ \\ \\ \\ | _ | 20 | _ | - ns |
| | Turn-on time | t _{on} | | | 40 | _ | |
| | Fall time | t _f | | | 10 | _ | |
| | Turn-off time | t _{off} | | _ | 40 | _ | |
| Total gate charge (gate-source plus gate-drain) | | Qg | | _ | 45 | _ | nC |
| Gate-source charge | | Q _{gs} | $V_{DD} \simeq 120 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 30 \text{ A}$ | _ | 21 | _ | |
| Gate-drain ("miller") charge | | Q _{gd} | | | 24 | | |

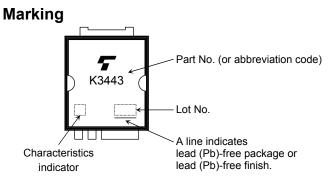
Note 4: Connect the S1 and S2 pins together, and ground them except during switching time measurement.

Source-Drain Diode Ratings and Characteristics (Note 5) (Ta = 25°C)

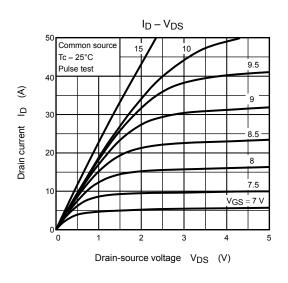
| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|--|--------------------|--|-----|------|------|------|
| Continuous drain reverse current (Note 1, Note 5) | I _{DR} 1 | — | _ | _ | 30 | А |
| Pulse drain reverse current (Note 1, Note 5) | I _{DRP} 1 | — | _ | _ | 120 | А |
| Continuous drain reverse current (Note 1, Note 5) | I _{DR} 2 | — | _ | _ | 1 | А |
| Pulse drain reverse current (Note 1, Note 5) | I _{DRP} 2 | — | _ | _ | 4 | А |
| Forward voltage (diode) | V _{DS2F} | I _{DR1} = 30 A, V _{GS} = 0 V | _ | _ | -1.5 | V |
| Reverse recovery time | t _{rr} | $I_{DR} = 30 \text{ A}, V_{GS} = 0 \text{ V},$ | _ | 250 | _ | ns |
| Reverse recovery charge | Qrr | dl _{DR} /dt = 100 A/μs | _ | 1.75 | _ | μC |

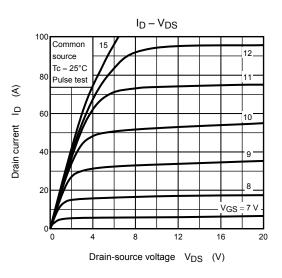
Note 5: I_{DR} 1, I_{DRP} 1: Current flowing between the drain and the S2 pin. Ensure that the S1 pin is left open. I_{DR} 2, I_{DRP} 2: Current flowing between the drain and the S1 pin. Ensure that the S2 pin is left open.

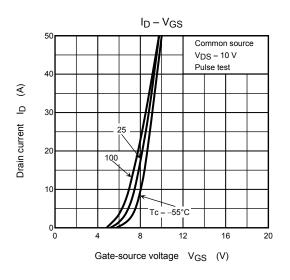
Unless otherwise specified, connect the S1 and S2 pins together, and ground them.

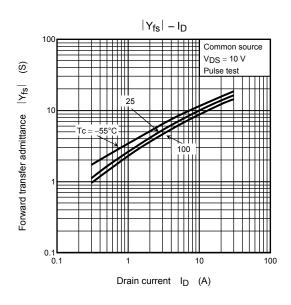


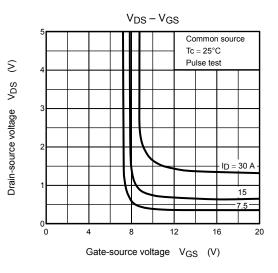
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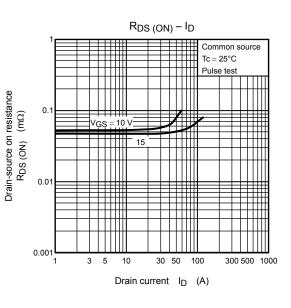




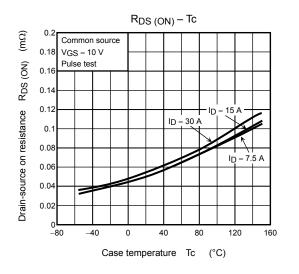


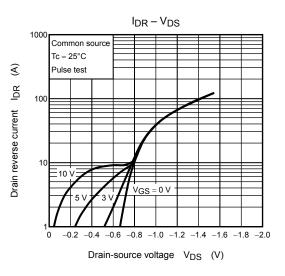


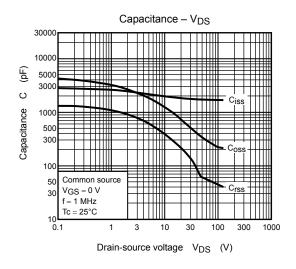


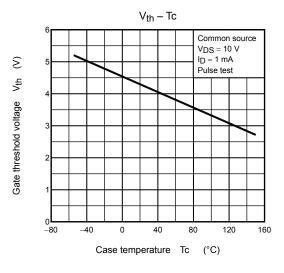


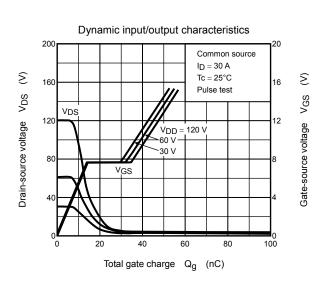
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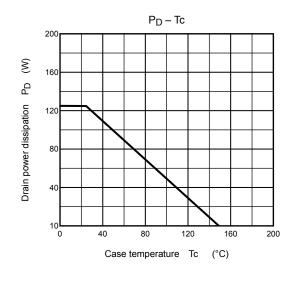


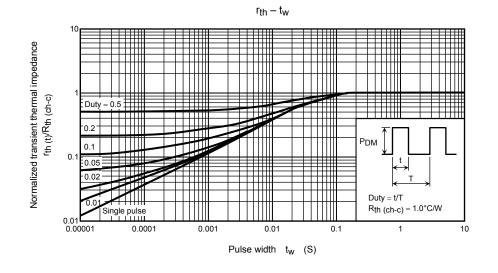




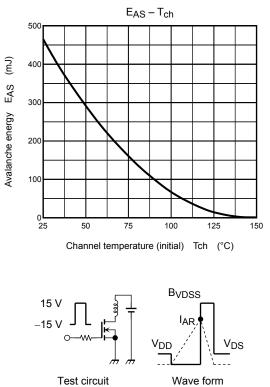








Safe operating area 300 ID max (pulsed) 100 100 μs 30 ms E 11 DC. ation ₽ 10 25°C Тс Drain current -----* Single nonrepetitive pulse 0.3 $\text{Tc}=25^{\circ}\text{C}$ Curves must be derated linearly | | | | | | with increase in temperature. VDSS max 0.1 3 10 30 100 300 Drain-source voltage V_{DS} (V)



Test circuit

 $E_{AS} = \frac{1}{2} \cdot L \cdot l^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$ $R_G = 25 \Omega$ V_{DD} = 50 V, L = 773 μH

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20070701-EN

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